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INTERNATIONAL STANDARD

IEC 60191-6-8

First edition 2001-08

Mechanical standardization of semiconductor devices –

Part 6-8:

General rules for the preparation of outline drawings of surface mounted semiconductor device packages – Design guide for glass sealed ceramic quad flatpack (G-QFP)

Normalisation mécanique des dispositifs à semiconducteurs

Partie 6-8:

Règles générales pour la préparation des dessins d'encombrement des dispositifs à semiconducteurs à montage en surface – Guide de conception pour les boîtiers plats quadrangulaires en céramique, scellement verre



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MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES -

Part 6-8: General rules for the preparation of outline drawings of surface mounted semiconductor device packages – Design guide for glass sealed ceramic quad flatpack (G-QFP)

FOREWORD

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International Standard IEC 60191-6-8 has been prepared by subcommittee 47D: Mechanical standardization of semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47D/438/FDIS	47D/456/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication will remain unchanged until 2005. At this date, the publication will be

- reconfirmed;
- withdrawn;
- · replaced by a revised edition, or
- amended.

A bilingual version of this standard may be issued at a later date.

MECHANICAL STANDARDIZATION OF SEMICONDUCTOR DEVICES -

Part 6-8: General rules for the preparation of outline drawings of surface mounted semiconductor device packages – Design guide for glass sealed ceramic quad flatpack (G-QFP)

1 Scope and object

This part of IEC 60191 provides the common outline drawings and dimensions for all types of structures and composed materials of glass sealed ceramic quad flatpack (hereinafter called G-QFP).

The object of this design guide is to standardize outlines and obtain interchangeability of G-QFP.

2 Normative references

The following normative documents contain provisions which, through reference in this text, constitute provisions of this part of IEC 60191. For dated references, subsequent amendments to, or revisions of, any of these publications do not apply. However, parties to agreements based on this part of IEC 60191 are encouraged to investigate the possibility of applying the most recent editions of the normative documents indicated below. For undated references, the latest edition of the normative document referred to applies. Members of IEC and ISO maintain registers of currently valid International Standards.

IEC 60191 (all parts), Mechanical standardization of semiconductor devices

3 Definitions

For the purpose of this part of IEC 60191, the following definition, as well as those given in the other parts of this standard, apply.

3.1 G-QFP

glass sealed package with gull-wing formed terminals which are led out in four directions to mount on PCB surface

4 Numbering of the pins

The index area is positioned at the upper left corner of the package body when it is viewed from the seating plane. The terminal that is closest to the index corner is numbered 1, and continued terminals that count in counter-clockwise directions are numbered 2, 3.

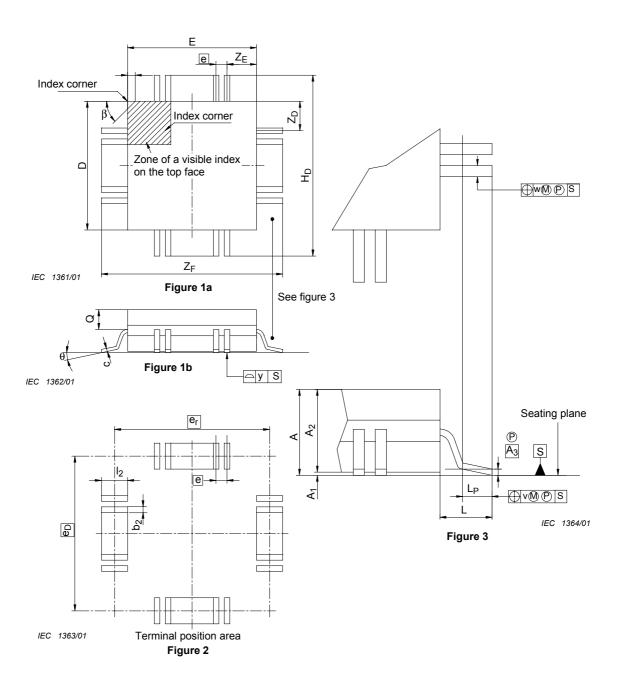


Table 1 – Group 1: Dimensions appropriate to mounting and interchangeability

Ref.	Limits	imits to be observed		Recommended values for the dimensions			
Kei.	Min.	Nom.	Max.	mm	Note		
n		Х			1		
n _D		Х			1		
n _E		Х			1		
Α			Х	A max. = 0,5 × m	2		
				m = 3, 4, 5, 6, 7, 8, 9, 10, 11			
A1	X	X	x	A1 _{min} 0,00 0,25			
				A1 nom 0,10 0,40			
				A1 _{max} 0,25 0,50			
				max ,			
A2	X	X	x	A2 _{min} 0,51 1,01 1,51 2,01 2,51			
				A2 nom 0,76 1,26 1,76 2,26 2,76			
				A2 max 1,00 1,50 2,00 2,50 3,00			
				A2 _{min} 3,01 3,51 4,01 4,51			
				A2 _{nom} 3,26 3,76 4,26 4,76			
				A2 _{max} 3,50 4,00 4,50 5,00			
A_3		Х		$A_3 = 0.25$			
b_p	Х	X	X	e b _{p min} b _{p nom} b _{p max}			
				1,0 0,35 0,42 0,50			
				0,8 0,30 0,37 0,45			
				0,65 0,25 0,32 0,40			
				0,5 0,15 0,22 0,30			
				0,4 0,15 0,18 0,22			
D		X		E nom D nom	4		
				$5 \times K - 0.8$ K = 2, 4			
E		Х		Regular $6 \times K - 0.8$ $m = 3, 4, 5$			
				square $7 \times K - 0.8$			
				20 + 4m - 0,8			
				Rectangular $7 \times K - 0.8$ $5 \times 2K - 0.8$			
				E _{nom} × D _{nom}			
				Square Rectangular			
				$9,2 \times 9,2$ $13,2 \times 19,2$			
				11,2 × 11,2 27,2 × 39,2			
				13,2 × 13,2			
				19,2 × 19,2 23,2 × 23,2			
				27,2 × 27,2			
				31,2 × 31,2			
				35,2 × 35,2			
				39,2 × 39,2			

Table 1 (continued)

Ref.	Limits	to be ob	served	Recommended values for the dimensions	Note a
Kei.	Min.	Nom.	Max.	mm	Note a
е		Х		e nom. = 1,0; 0,8; 0,65; 0,5; 0,4	5
H_D	X	Х	Х	$H_{D \text{ nom}} = D_{\text{ nom}} + 2L_{\text{ nom}}$	
				$H_{D min} = D_{nom} - 0.2$	
				$H_{D \text{ max}} = D_{\text{ nom}} + 0.2$	
H _E	X	X	Х	$H_{E \text{ nom}} = E_{\text{ nom}} + 2L_{\text{ nom}}$	
				$H_{E min} = H_{E nom} - 0.2$	
				$H_{E max} = H_{E nom} + 0.2$	
L		Х		L _{nom} = 1,8; 2,1; 2,4	
L _p	x	x	х	L nom Lp min Lp nom Lp max 1,8, 2,1 0,45 0,60 0,75 2,4 0,73 0,88 1,03	
٧			Х	v _{max} = 0,3	6
w			х	e w max e w max 1,0 0,20 0,5 0,10 0,8 0,16 0,4 0,10 0,65 0,13	6
у			Х	y _{max} = 0,10	
θ	Х	Х	Х	$\theta_{min} = 0^{\circ}$ $\theta_{nom} = 3^{\circ}$ $\theta_{max} = 10^{\circ}$	
^a See	notes or	pages 9	and 10.		

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Table 2 – Group 2: Dimensions appropriate to mounting and gauging

Ref.	Limits	to be ob	served	Recommended values for the dimensions	Note 2
Rei.	Min.	Nom.	Max.	mm	Note a
b ₂			Х	$b_{2 \text{ max}} = b_{p \text{ max}} + W_{\text{max}}$	
				e b _{2 max}	
				1,00 0,70	
				0,80 0,61	
				0,65 0,53	
				0,50 0,40	
				0,40 0,32	
е		Х		e nom = 1,0; 0,8; 0,65; 0,5; 0,4	5
e_D		X		$e_D = H_{D \text{ nom}} - L_{p \text{ nom}}$	
e_{E}		Х		e _E = H _{E nom} - L _{p nom}	
l ₂			х	$I_{2 \text{ max}} = L_{p \text{ max}} + V_{\text{max}}$	
				L _{nom} I _{2 max}	
				1,8; 2,1 1,05	
				2,4 1,33	
a See	notes or	n pages 9	and 10		

Table 3 - Group 3: Dimensions appropriate to automated handling

Ref.	Limits	Limits to be observed		Recommended values for the dimensions	Note			
Kei.	Min.	Nom.	Max.	mm	Note			
A ₂	X	Х	Х	A _{2 min} 0,51 1,01 1,51 2,01 2,51				
				A _{2 nom} 0,76 1,26 1,76 2,26 2,76				
				A _{2 max} 1,00 1,50 2,00 2,50 3,00				
				A _{2 min} 3,01 3,51 4,01 4,51				
				A _{2 nom} 3,26 3,76 4,26 4,76				
				A _{2 max} 3,50 4,00 4,50 5,00				
D	Х		Х	$D_{min} = D_{nom} - 0.3$				
				$D_{max} = D_{nom} + 0.3$				
E	X		X	$E_{min} = E_{nom} - 0.3$				
				$E_{max} = E_{nom} + 0.3$				
k	Х			No definition				
Q	Х			No definition				
β		Х		β = 45°				

Table 4 - Group 4: Dimensions for information only

Ref.	Limits	to be ob	served	Recommended values for the dimensions	Note a
Kei.	Min.	Nom.	Max.	mm	Note a
С	х		x	$ \begin{array}{ c c c c c } \hline e & c_{min} & c_{max} \\ \hline e \geq 0.65 & 0.12 & 0.23 \\ \hline e \leq 0.50 & 0.10 & 0.20 \\ \hline \end{array} $	7
Z _D		Х	Х	$Z_{D \text{ nom}} = (D_{\text{nom}} - (n_D - 1) e) / 2$ $Z_{D \text{ max}} = (D_{\text{max}} - (n_D - 1) e) / 2$	8
Z _E		Х	Х	$Z_{E \text{ nom}} = (E_{nom} - (n_E - 1) e) / 2$ $Z_{E \text{ max}} = (E_{max} - (n_E - 1) e) / 2$	8
^a See	notes or	pages 9	and 10.		•

NOTE 1 The relation between the package body size and the maximum number of terminals will be as shown in the following table.

a) Regular square shape series

E × D*	$n_{nom} (n_{D nom} = n_{E nom} = n_{nom} / 4)$								
е	1,00	0,80	0,65	0,50	0,40				
10 × 10	36	44	52	64	80				
12 × 12		48	64	80	100				
14 × 14	52	64	80	100	120				
20 × 20	76	88	112	144	176				
24 × 24				176	216				
28 × 28		128	160	208	256				
32 × 32			184	240	296				
36 × 36				272	336				
40 × 40			232	304	376				

b) Rectangular shape series

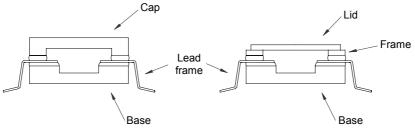
E x D a		n _{nom} (n _{D nom} , n _{E nom})						
е	1,00	0,80	0,65	0,50	0,40			
14 × 20	64 (13, 19)	80 (16, 24)	100 (20,30)					
28 × 40				256 (52,76)				

^a The E, D values shown in this table indicate integral numbers (as shown) minus 0,8 mm.

NOTE 2 The values stipulated by the mathematical expression must be applied to the individual overall dimensional standards.

NOTE 3 The following values are recommended for the thickness of the ceramic excluding the sealing glass.

Base	1,27
Сар	1,27
Frame	0,76
Lid	0,76



IEC 1365/01

NOTE 4 Seal mismatching and glass protrusion are not included.

NOTE 5 Stipulates the true geometrical position.

NOTE 6 The values v, w are stipulated as volume V or volume W without A and datum B from figure 1a.

without A, B as a datum line, and eliminate datum

The reasons are as follows.

a) Generally, in the case of ceramic packages, a tolerance of the outside dimensions is wider than that of plastic moulded package. Therefore, the lead true position based on ceramic body dimension is a rather large value like 0,6 mm, generally.

These large values v and w are not useful for users.

- b) E and D, the package outside dimension of G-QFP, do not include seal mismatching and glass protrusion according to note 4, so it is meaningless to specify E and D as datum planes.
- c) In the semiconductor industry, QFP type packages are handled not by package body, but by the tip of the lead frame, in general.

For instance, QFP is handled in electrical tests or mounting onto printed circuit board by lead frame as a base point, not by package body, especially for a high-pin-count/fine-pitch QFP.

Therefore, it is not so significant to stipulate package width/length as a datum line.

NOTE 7 These values include the thickness of finish plating.

NOTE 8 Since in the G-QFP the part corresponding to this dimension is not the outermost side of the package, the seal mismatching and the glass protrusion are not included, and only the standard values are stipulated.

NOTE 9 The pin layout is determined as follows.

E × D	е	Terminal layout
- 10 × 10 10 × 10 14 × 14 12 × 12	1,00 0,80 0,65 0,50 0,40	The package centre coincides with the terminal centre.
Other combinatio and e besides the mentioned ones		The terminal centre is deviated by e /2 from the package centre.

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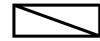
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